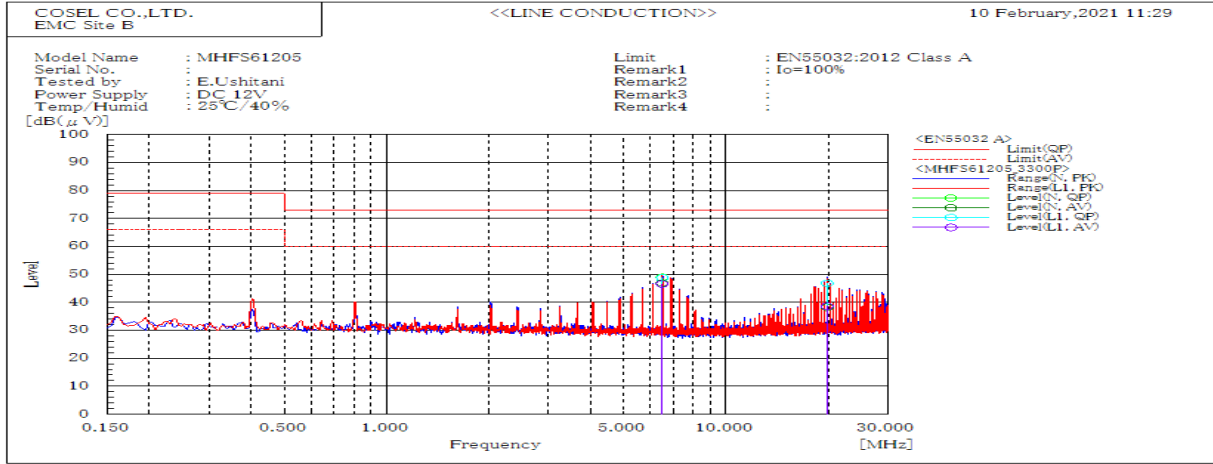
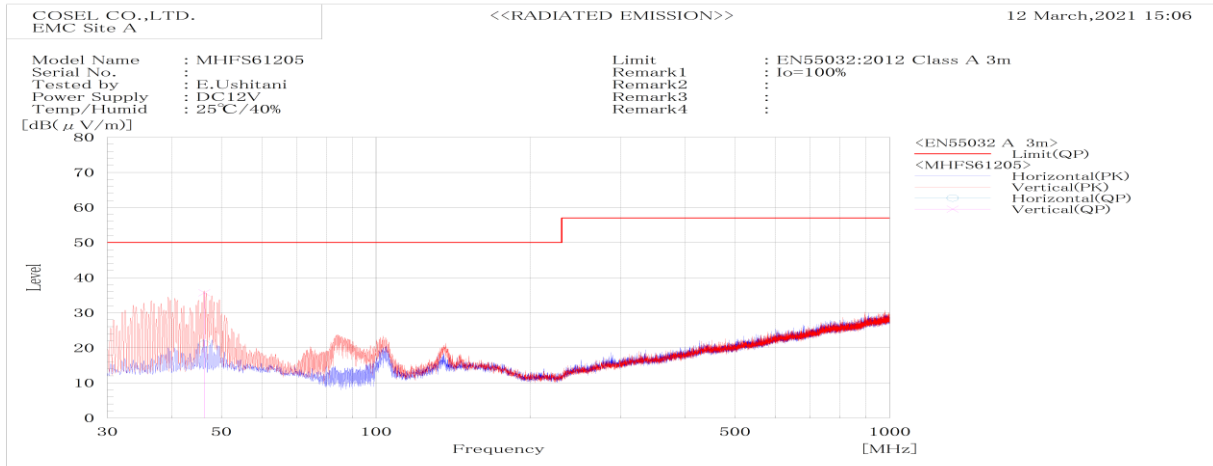


DATA SHEET		Date	05-Nov-21
Model	MHFS61205	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



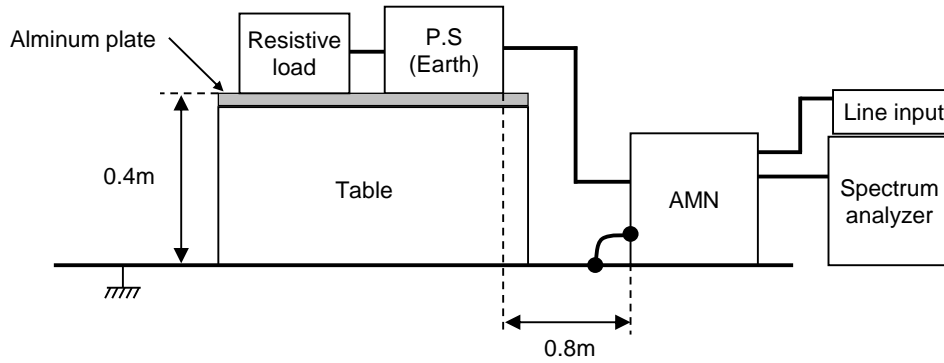
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
6.488	L1	48.7	46.6	73	60	24.3	13.4	Pass	
19.871	L1	46.8	38.6	73	60	26.2	21.4	Pass	
6.487	N	48.9	46.9	73	60	24.1	13.1	Pass	
19.859	N	46.8	38.2	73	60	26.2	21.8	Pass	



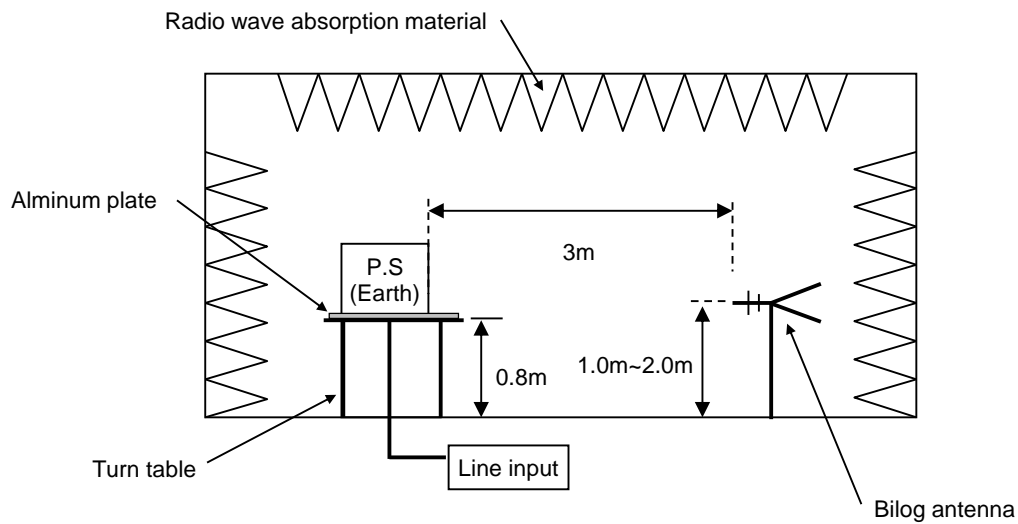
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Limit dB(uV/m)		Margin dB		Pass/Fail	Height cm	Angle deg	Remark
			QP	AV	QP	AV	QP	AV				
46.332	H	Stable	21.1	50	28.9	Pass	100.2	22.3				
46.329	V	Stable	35.7	50	14.3	Pass	100.4	340.2				

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

**1. Line conduction**



**2. Radiated emission**

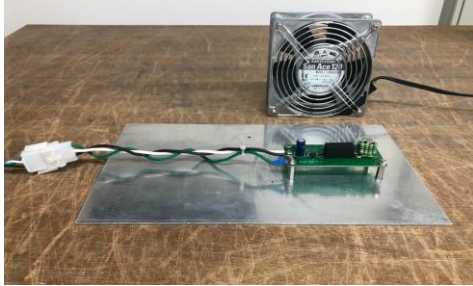


### Conditions

Test : EMI  
 Model Name: MHFS6□□

○Photographs of Test Set-Up

#### LINE CONDUCTION



#### RADIATED EMISSION



○Testing circuitry

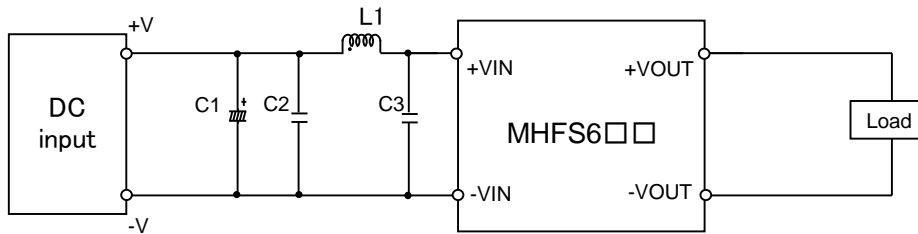


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 $\mu$ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 $\mu$ H Inductor(LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 $\mu$ H Inductor(LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 $\mu$ H Inductor(LQH5BPN220MT0 MURATA MANUFACTURING)